

产 品 规 格 书

SPECIFICATIONS FOR PRODUCT

产品类型 TYPE: Crystal Oscillator

产品规格 SPEC: 25MHz/3225/1.8V

产品型号 P/N : CJO05-250001820B30

日期 DATE: 2019/11/19

核准及签名			部门
R&D APPR. SIGNATURED			DEPT.
拟制	审核	批准	频率器件事业部
ISSUE	CHECK	APPROVAL	
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**SMD3.2 * 2.5 Crystal Oscillator****CJO05-250001820B30****1. Scope:**

- 1.1 This specification applies to the RoHS crystal oscillator with a frequency of 25MHz which will be used in electronic equipment.

2. Construction:

- 2.1 Oscillators series: SMD 3.2×2.5 XO
2.2 Package: SMD 3.2×2.5

3. Electrical Characteristics

- | | | |
|------|---|---|
| 3.1 | Nominal Frequency: | 25.000MHz |
| 3.2 | Frequency Stability:
(incl. 25°C tolerance) | ±20ppm |
| 3.3 | Aging: | ±3ppm/year |
| 3.4 | Operating Temperature Range: | -40°C to +85°C |
| 3.5 | Storage Temperature Range: | -55°C to +125°C |
| 3.6 | Input Voltage (V_{DD}): | +1.8 Vdc±10% |
| 3.7 | Input Current (I_{DD}): | 10mA max |
| 3.8 | Output Waveform: | CMOS |
| 3.9 | Output Symmetry: | 50±10% |
| 3.10 | Rise/Fall Time: | 5ns max |
| 3.11 | Output Voltage V_{OL} :
V_{OH} : | 10%VDD
90%VDD |
| 3.12 | Output Load: | 15pF |
| 3.13 | Output State Control: | Enable/disable |
| 3.14 | Start-up Time: | 5ms max |
| 3.15 | Standby current: | 10μA max |
| 3.16 | Phase Jitter (rms): | 1ps rms max 12kHz to 20MHz max |
| 3.17 | Oscillation mode: | A1 |
| 3.18 | Others: | Not recommended for safety applications |

4. Reliability Specifications

This is the quality control and quality assurance and reliability tests performance data for the RoHS 25MHz SMD 3.2×2.5 XO

related to the specification and approval sheet provided by JSCJ .

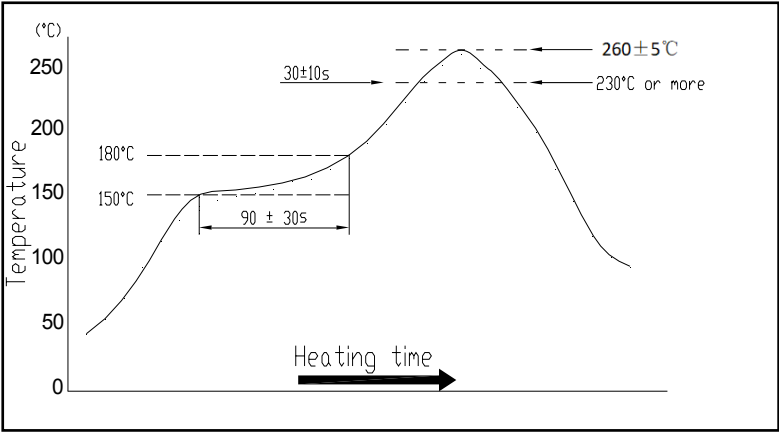
Standard test condition (TEMP.: 20±15°C. Relative humidity: 65±20%)

For any discrepancy in GO/NG, test will be done at TEMP.25±2°C. R.H. 65±5%.

NO.	ITEM	SPECIFICATION	TEST METHOD
4.1	Temperature Cycle (GB/T 2423.22-2002, Method Nb)	Frequency change after test≤± 5ppm.	10 cycles from -55°C to 125°C. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.2	Low Temperature Storage (GB/T 2423.1-2001, Method Aa)	Frequency change after test≤± 5ppm.	Spending 72 hrs at -55°C±3°C constant temperature. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.3	High Temperature Storage (GB/T 2423.2-2001, Method Ba)	Frequency change after test≤± 5ppm.	Spending 72 hrs at 125°C±3°C constant temperature. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.4	Humidity (GB/T 2423.3-2006, Method Cab)	Frequency change after test≤± 5ppm.	Spending 96 hrs at 40 °C ± 3 °C, with 90± 3% R.H. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.5	Vibration (GB/T 2423.10-1995, Method Fc)	Frequency change after test≤± 5ppm.	Apply 0.75mm vibration at sweep frequency 10~500 Hz, for 2h. 10 cycles in each direction of 3 axis. Measurement taken after 1 hour.
4.6	Shock (GB/T 2423.5-1995, Method Ea)	Frequency change after test≤± 5ppm. No visible damages.	Peak 1000m/s ² , normal width 6ms half sine wave form, 3.7m/s, 3 perpendicular axis of samples, 3 cycles / direction, total 18 cycles. Measurement taken after 1 hour.
4.7	Drop (GB/T 2423.8-1995, Method Ed)	Frequency change after test≤± 5ppm. No visible damages.	Free drop to the wooden plate from 1.0 m heights for 3 times.
4.8	Solderability (GB/T 2423.28-2005, Method Tc)	Terminals shall be covered more then 95% with solder.	In 245 ± 5°C solder bath for 2 ± 0.5 seconds. There is no need to do functioned test. 8-12X magnifier.
4.9	Terminal Strength (JIS-C-6429 Method 1 & 2)	No visible damage	Mount on a glass-epoxy board (100x50x1.6mm), then bend to 2mm displacement (velocity 1mm/sec) and keep for 5 seconds. or pulling force 0.5 kg for at least 60 seconds.
4.10	Resistance to Soldering Heat (GB/T 2423.28-2005, Test Tb Method 1B)	Frequency change after test≤± 5ppm.	Passed through the re-flow oven under the following condition. Preheat to 150°C±5°C for 60 to 120sec, and peak 265°C±5°C for 10s±3sec. Measurement taken after DUT being left at room temperature for at 24±2 hours.
4.11	OTHERS		

5. Recommended Reflow soldering condition (SMD)

■ Solder profile
Peak: 260±5℃ Soldering zone: 230℃ or more, 30±10s.
Pre-heating zone 1: 150~180℃, 90±30s



Temperature profile for reflow soldering

6. Soldering iron method

Bit temperature: 350±10℃ Application time of soldering iron:3+1 s
For other procedures, refer to IEC 60068-2-20.

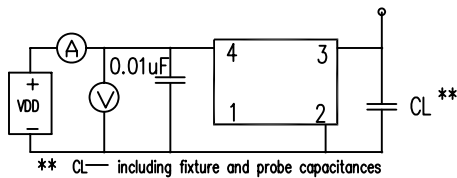
PIN CONNECTION

P/N	CJO05
1	Enable/Disable*
2	GND
3	Output
4	VDD

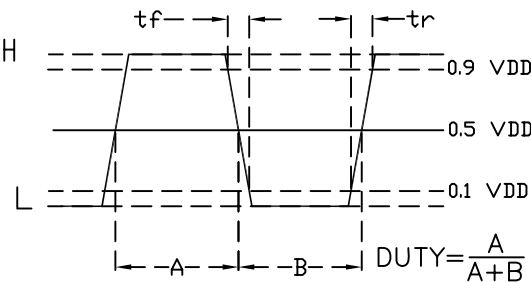
Enable/Disable functional description
When pin1 goes high ($\geq 0.7V_{DD}$) or open, the Oscillator in normal operation and has output in frequency. When pin1 goes low ($\leq 0.3V_{DD}$), the oscillator stops and the oscillator output (Pin3) becomes high impedance.

*

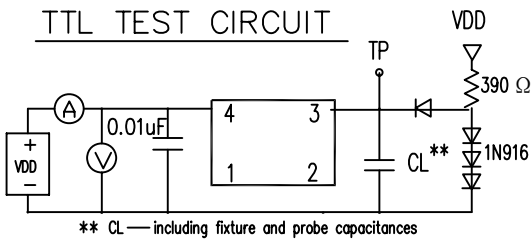
CMOS TEST CIRCUIT



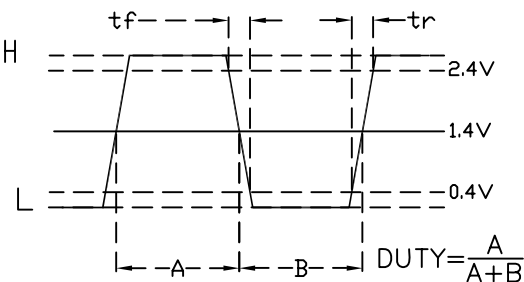
TYPICAL CMOS WAVE FORM



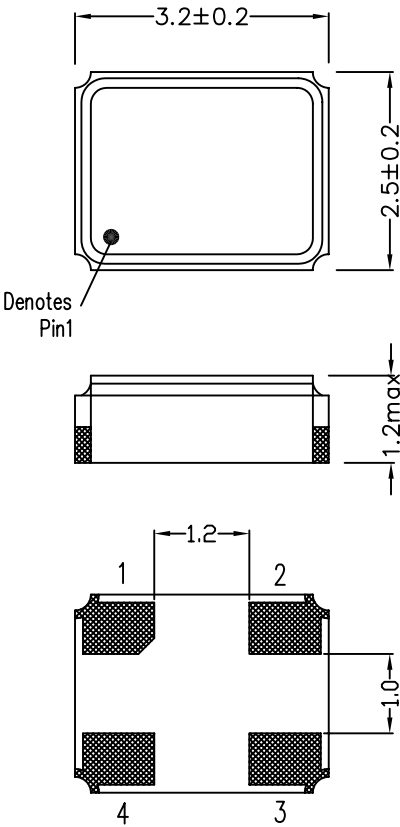
TTL TEST CIRCUIT



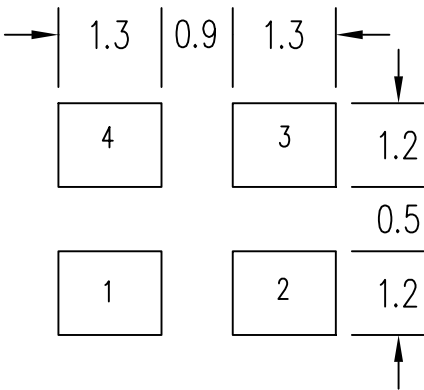
TYPICAL TTL WAVE FORM



Package Outline Dimensions

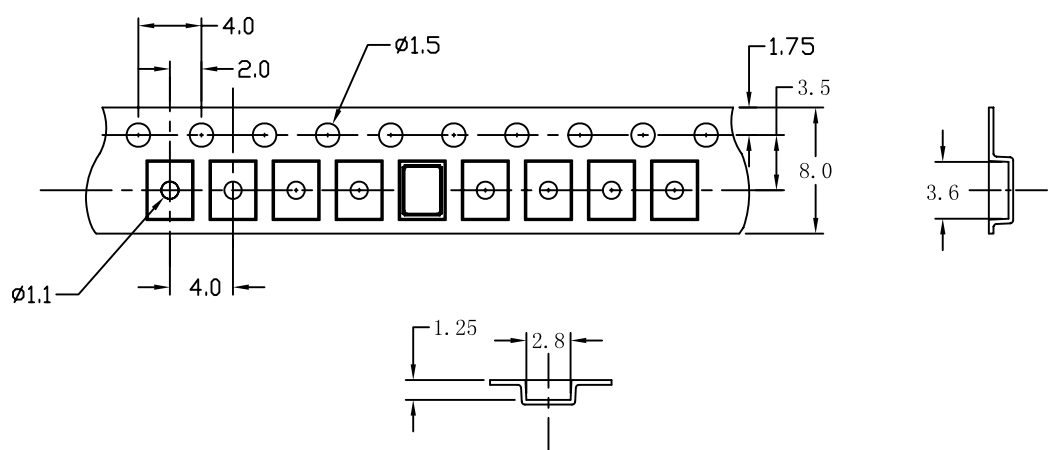
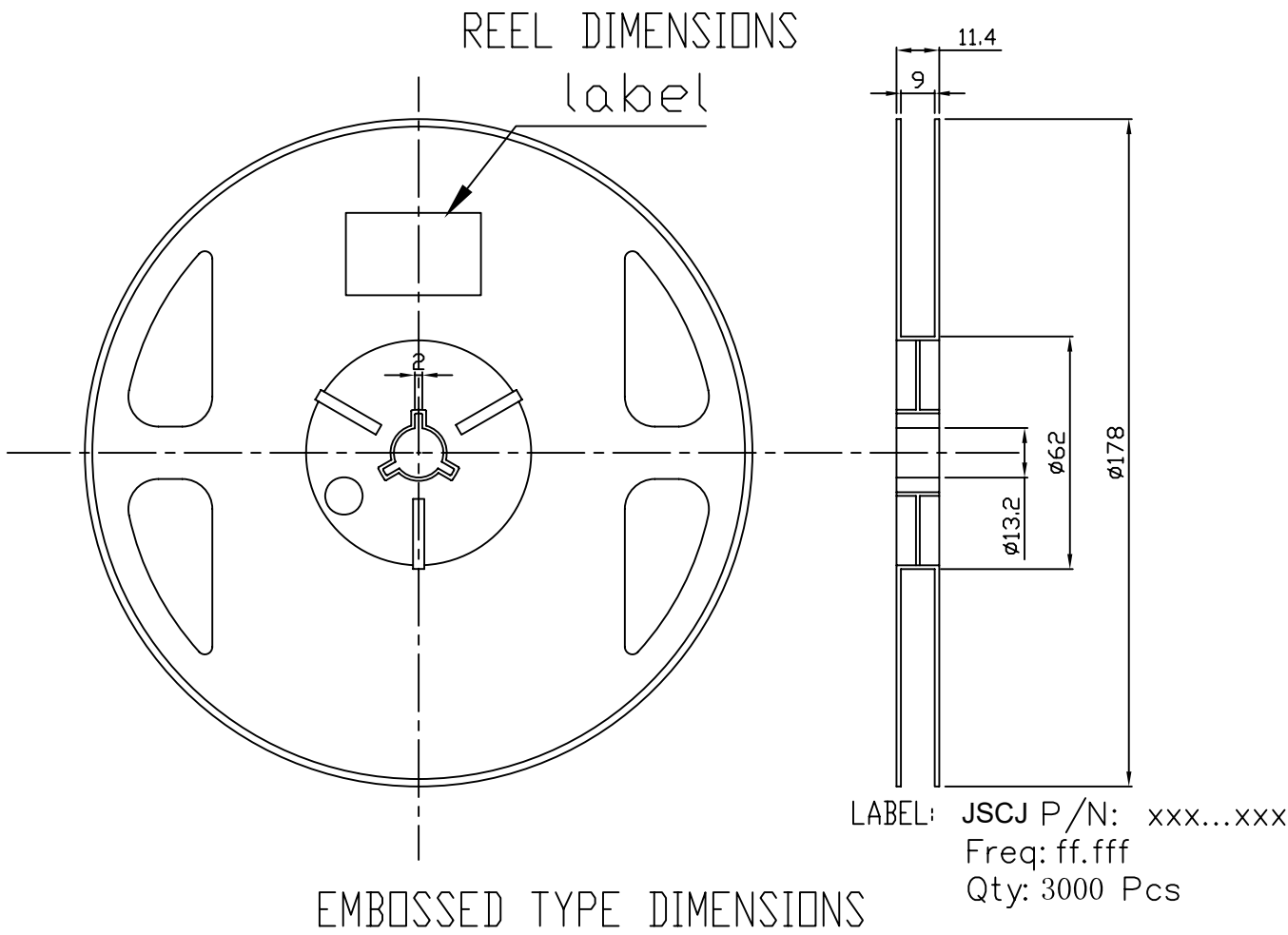


Suggested Pad Layout



NOTICE

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USER FEED DIRECTION